NSN 6650-01-316-1191

Scanning Electron Microscope - Page 1 of 1



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General Description:

Shelf Life:

Demilitarization: Yes - demil/mli

Digital imaging; computerr controlled; used for microcircuit failure analysis; c/o electron optical console: electron optical column, specimen chamber, specimen stage, vacuum system and vibration isolation system, and electronics and display console: main control panel, display and record camera system plus electronic components

N/a	
Unit Of Measure:	